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 Members of the Texas Instruments Widebus™ Family 	SN54AHC16541 DO SN74AHC16541 DO (TOP \	GG OR DL PACKAGE
 Operating Range 2-V to 5.5-V V_{CC} 		
 EPIC[™] (Enhanced-Performance Implanted 	10E1 1	48 10E2
CMOS) Process	1Y1 🛛 2	47 0 1A1
 Distributed V_{CC} and GND Pin Configuration 	1Y2 🛛 3	46 0 1A2
Minimizes High-Speed Switching Noise	GND 🛛 4	45 GND
 Flow-Through Architecture Optimizes PCB 	1Y3 🛛 5	44 🛛 1A3
Layout	1Y4 🕻 6	43 🛛 1A4
 Package Options Include Plastic 300-mil 	V _{CC} [] 7	42 V _{CC}
Shrink Small-Outline (DL) and Thin Shrink	1Y5 🛿 8	41 🛛 1A5
Small-Outline (DGG) Packages and 380-mil	1Y6 🛛 9	40 🛛 1A6
Fine-Pitch Ceramic Flat (WD) Package	GND 🛿 10	39 🛛 GND
Using 25-mil Center-to-Center Spacings	1Y7 🛿 11	38 🛛 1A7
g	1Y8 🛛 12	37 🛛 1A8
description	2Y1 🛛 13	36 🛛 2A1
•	2Y2 🛿 14	35 🛛 2A2
The 'AHC16541 are noninverting 16-bit buffers	GND 🛿 15	34 🛛 GND
composed of two 8-bit sections with separate	2Y3 🛛 16	33 🛛 2A3

d

output-enable signals. For either 8-bit buffer section, the two output-enable (10E1 and 10E2 or 20E1 and 20E2) inputs must be low for the corresponding Y outputs to be active. If either output-enable input is high, the outputs of that 8-bit buffer section are in the high-impedance state.

The SN54AHC16541 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AHC16541 is characterized for operation from -40°C to 85°C.

10E1	Ц	1	U	48	10E2
1Y1				-	
	_				_
1Y2	_	-			1A2
GND					GND
1Y3	Ц	5			1A3
1Y4	_				1A4
V _{CC}		7		42]v _{cc}
1Y5	Ц	8			1A5
1Y6					1A6
GND	Ц	10		39	GND
1Y7	C	11		38	1A7
1Y8	C	12		37	1A8
2Y1	C	13		36	2A1
2Y2	C	14		35	2A2
GND				34	GND
2Y3		16		33	2A3
2Y4	_			32	2A4
V _{CC}]v _{cc}
2Y5		19		30	2A5
2Y6					2A6
GND					GND
2Y7					2A7
2Y8	Ц	23			2A8
20E1	[24		25	20E2

FUNCTION TABLE	
(each 8-bit section)	

	INPUTS		OUTPUT
OE1	OE2	Α	Y
L	L	L	L
L	L	Н	н
н	Х	Х	Z
Х	Н	Х	Z



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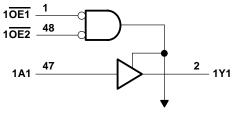
SN54AHC16541, SN74AHC16541 **16-BIT BUFFERS/DRIVERS** WITH 3-STATE OUTPUTS SCLS332B – MARCH 1996 – REVISED JUNE 1997

logic symbol[†]

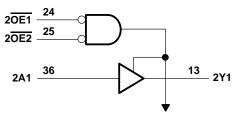
10E1	1	&			
10E2	48		EN1		
20E1	24	&			
20E1 20E2	25		EN2		
2022					
1A1	47		1 ⊽	2	1Y1
1A1	46			3	1Y2
1A2	44			5	1Y3
1A3	43			6	1Y4
1A5	41			8	1Y5
1A6	40			9	1Y6
1A7	38			11	1Y7
1A8	37			12	1Y8
2A1	36		I 2 ⊽	13	2Y1
2A2	35		. 2 .	14	2Y2
2A3	33			16	2Y3
2A4	32			17	210 2Y4
2A5	30			19	2Y5
2A6	29			20	2Y6
2A7	27			22	2Y7
2A8	26			23	2Y8

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels



To Seven Other Channels



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} Input voltage range, V_I (see Note 1) Output voltage range, V_O (see Note 1) Input clamp current, I_{IK} ($V_I < 0$) Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) Continuous output current, I_O ($V_O = 0$ to V_{CC}) Continuous current through each V_{CC} or GND Package thermal impedance, θ_{JA} (see Note 2): DGG package DL package	$\begin{array}{cccc} -0.5 \ V \ to \ 7 \ V \\ -0.5 \ V \ to \ V_{CC} + 0.5 \ V \\ -20 \ mA \\ \pm 20 \ mA \\ \pm 20 \ mA \\ \pm 25 \ mA \\ \pm 75 \ mA \\ 89^\circ C/W \\ -0.00 \ W \\ \end{array}$
Storage temperature range, T _{stg}	

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

			SN54AH	C16541	SN74AH0	C16541	LINUT	
			MIN	MAX	MIN	MAX	UNIT	
VCC	Supply voltage		2	5.5	2	5.5	V	
		V _{CC} = 2 V	1.5		1.5			
VIH	High-level input voltage	$V_{CC} = 3 V$	2.1		2.1		V	
		$V_{CC} = 5.5 V$	3.85		3.85			
		$V_{CC} = 2 V$		0.5		0.5		
VIL	Low-level input voltage	$V_{CC} = 3 V$		0.9		0.9	V	
		V _{CC} = 5.5 V		1.65		1.65		
VI	Input voltage		0	5.5	0	5.5	V	
Vo	Output voltage		0	VCC	0	VCC	V	
		$V_{CC} = 2 V$		-50		-50	μΑ	
ЮН	High-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		-4		-4		
		V_{CC} = 5 V ± 0.5 V		-8		-8	mA	
		V _{CC} = 2 V		50		50	μΑ	
IOL	Low-level output current	V_{CC} = 3.3 V ± 0.3 V		4		4		
		V_{CC} = 5 V ± 0.5 V		8		8	mA	
A #/ A > /	Insuit transition rise or fell rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		100		100	no //	
Δt/Δv	Input transition rise or fall rate	V_{CC} = 5 V ± 0.5 V		20		20	ns/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA	RAMETER	TEST CONDITIONS	N.	T,	ς = 25°C	;	SN54AH0	C16541	SN74AHC	C16541	UNIT
F#		TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
			2 V	1.9	2		1.9		1.9		
		IOH = -50 μA	3 V	2.9	3		2.9		2.9		
Vон			4.5 V	4.4	4.5		4.4		4.4		V
		I _{OH} = -4 mA	3 V	2.58			2.48		2.48		
		I _{OH} = –8 mA	4.5 V	3.94			3.8		3.8		
		I _{OL} = 50 μA	2 V			0.1		0.1		0.1	
			3 V			0.1		0.1		0.1	V
VOL			4.5 V			0.1		0.1		0.1	
		I _{OL} = 4 mA	3 V			0.36		0.5		0.44	
		I _{OL} = 8 mA	4.5 V			0.36		0.5		0.44	
ı.	Data inputs	VI = V _{CC} or GND	5.5 V			±0.1		±1		±1	μA
łı	Control inputs		5.5 V			±0.1		±1		±1	μΑ
Ioz		$V_O = V_{CC}$ or GND, $V_I (\overline{OE}) = V_{IL}$ or V_{IH}	5.5 V			±0.25		±2.5		±2.5	μΑ
ICC		$V_{I} = V_{CC} \text{ or GND}, I_{O} = 0$	5.5 V			4		40		40	μΑ
Ci		$V_I = V_{CC}$ or GND	5 V		2	10				10	pF
Co		$V_{O} = V_{CC}$ or GND	5 V		4						pF

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

	FROM	то	LOAD	Τį	λ = 25°C	;	SN54AHC	16541	SN74AHC	C16541		
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
^t PLH [*]	А	Y	C _I = 15 pF		5	7	1	8.5	1	8.5	ns	
^t PHL*	A	T	CL = 15 pr		5	7	1	8.5	1	8.5	115	
^t PZH [*]	OE	Y	Ci – 15 pF		6	10.5	1	11	1	11	ns	
^t PZL [*]		T	C _L = 15 pF		6	10.5	1	11	1	11	115	
^t PHZ*	OE	Y	C _I = 15 pF		7	11	1	12	1	12	ns	
^t PLZ [*]		OL	I	CL = 15 pr		7	11	1	12	1	12	115
^t PLH	А	Y	$C_{\rm L} = 50 \rm pE$		7.5	10.5	1	12	1	12	20	
^t PHL	A	ř	CL = 50 pF		7.5	10.5	1	12	1	12	ns	
^t PZH	OE	Y	C ₁ = 50 pF		8	14	1	16	1	16	ns	
^t PZL	OE	OE	r	CL = 50 pr		8	14	1	16	1	16	115
^t PHZ	ŌĒ	Y	C ₁ = 50 pF		9	15.4	1	17.5	1	17.5	ns	
^t PLZ		Ť	CL = 50 pr		9	15.4	1	17.5	1	17.5	115	

* On products compliant to MIL-PRF-38535, this parameter is ensured but not production tested.



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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	ТА	= 25°C	;	SN54AHC	16541	SN74AHC	216541	UNIT		
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
^t PLH [*]	А	Y	C _I = 15 pF		3.5	5	1	6	1	6	ns		
^t PHL [*]	A	I	0 <u>[</u> = 15 pr		3.5	5	1	6	1	6	115		
^t PZH [*]	OE	Y	C _I = 15 pF		4.7	7.2	1	8.5	1	8.5	ns		
^t PZL*	OE	I	0 <u>[</u> = 15 pr		4.7	7.2	1	8.5	1	8.5	115		
^t PHZ [*]	OE	Y	C _I = 15 pF		5	7.5	1	8	1	8	20		
^t PLZ [*]		T	CL = 15 pr		5	7.5	1	8	1	8	ns		
^t PLH	А	Y			5	7	1	8	1	8			
^t PHL	A	ř	C _L = 50 pF		5	7	1	8	1	8	ns		
^t PZH		Y	$C_{\rm L} = 50 \rm pE$		6.2	9.2	1	10.5	1	10.5	20		
^t PZL	OE	OE	OE	Y CL = 50 pF	C _L = 50 pF		6.2	9.2	1	10.5	1	10.5	ns
^t PHZ	OE	Y	V	V	$C_{1} = 50 \text{ pc}$		6	8.8	1	10	1	10	ns
^t PLZ	UE	r	C _L = 50 pF		6	8.8	1	10	1	10	115		

* On products compliant to MIL-PRF-38535, this parameter is ensured but not production tested.

output-skew characteristics, C_L = 50 pF (see Note 4)

ſ					SN74AH				
	PARAMETER	METER FROM TO (INPUT) (OUTPUT)				Vcc	T _A = 25°C	MIN MAX	UNIT
			(001101)		MIN MAX				
ſ	*	٨	V	$3.3~V\pm0.3~V$	1.5	1.5	20		
	^t sk(o)	A		$5~V\pm0.5~V$	1	1	ns		

NOTE 4: Characteristics are determined during product characterization and ensured by design.

noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C (see Note 5)

	PARAMETER		SN74AHC16541		
	PARAMETER	MIN	MAX	UNIT	
VOL(P)	Quiet output, maximum dynamic V _{OL}		0.8	V	
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.8	V	
VOH(V)	Quiet output, minimum dynamic V _{OH}	4.7		V	
VIH(D)	High-level dynamic input voltage	3.5		V	
V _{IL(D)}	Low-level dynamic input voltage		1.5	V	

NOTE 5: Characteristics are determined during product characterization and ensured by design for surface-mount packages only.

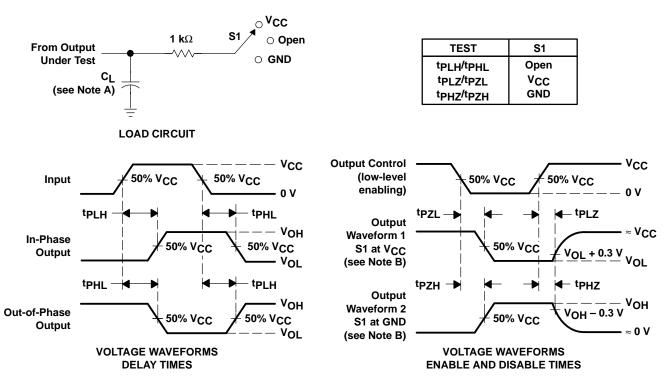
operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS		TYP	UNIT
C _{pd}	Power dissipation capacitance	No load,	f = 1 MHz	12	pF





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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r = 3 ns, t_f = 3 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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